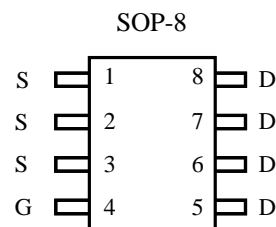


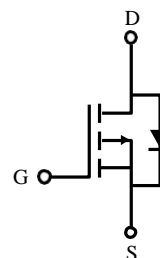
## P -Channel High Density Trench MOSFET

### Features:

- Super high dense cell trench design for low RDS(on).
- Rugged and reliable.
- Surface Mount package.



PRODUCT SUMMARY		
$V_{(BR)DSS}$	$R_{DS(on)}$ (m $\Omega$ ) Max	$I_D$
-30V	8 @ $V_{GS} = -10V$	-15A
	10.7 @ $V_{GS} = -4.5V$	



### ABSOLUTE MAXIMUM RATINGS (TA = 25 °C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous (Note 1)	$I_D$	$T_A = 25\text{ }^\circ\text{C}$	-15
		$T_A = 70\text{ }^\circ\text{C}$	-8.5
Pulse Drain Current (Note 2)	$I_{DM}$	-60	A
Avalanche Current	$I_{AS}$	-45	
Single Pulse Avalanche Energy	$E_{AS}$	95	
Maximum Power Dissipation (Note 1)	$P_D$	$T_A = 25\text{ }^\circ\text{C}$	2.5
		$T_A = 75\text{ }^\circ\text{C}$	1.6
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	- 55 to 150	$^\circ\text{C}$

### THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Case (Note 1)	$R_{thJC}$	30	$^\circ\text{C/W}$
Thermal Resistance, Junction-to-Ambient (Note 1)	$R_{thJA}$	75	$^\circ\text{C/W}$

Note:

1. Surface Mounted on FR4 Board ,  $t \leq 10\text{sec}$  .
2. Pulse width limited by maximum junction temperature

**ELECTRICAL CHARACTERISTICS (TA = 25 °C unless otherwise noted)**

Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0V, I_D = -250\mu A$	-30			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -24V, V_{GS} = 0V, T_j = 25^\circ C$			-1	uA
		$V_{DS} = -20V, V_{GS} = 0V, T_j = 125^\circ C$			-10	
Gate-Body Leakage	$I_{GSS}$	$V_{GS} = \pm 25V, V_{DS} = 0V$			$\pm 100$	nA
<b>ON CHARACTERISTICS (Note 3)</b>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\mu A$	-1	-1.5	-3	V
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = -10V, I_D = -12A$		6.5	8.0	m $\Omega$
		$V_{GS} = -4.5V, I_D = -10A$		8.2	10.7	m $\Omega$
Forward Transconductance	gfs	$V_{DS} = -10V, I_D = -12A$		24		S
<b>DYNAMIC CHARACTERISTICS (Note 4)</b>						
Input Capacitance	$C_{ISS}$	$V_{DS} = -15V, V_{GS} = 0V$ $f = 1.0MHz$		4330		pF
Output Capacitance	$C_{OSS}$			499		pF
Reverse Transfer Capacitance	$C_{RSS}$			373		pF
<b>SWITCHING CHARACTERISTICS (Note 4)</b>						
Turn-On Delay Time	$t_{d(ON)}$	$V_{DS} = -15V, I_D = -1A, V_{GS} = -10V, R_{GEN} = 6\Omega$		51.0		nS
Rise Time	tr			40.0		nS
Turn-Off Delay Time	$t_{d(OFF)}$			77.0		nS
Fall Time	tf			56.0		nS
Total Gate Charge	Qg	$V_{DS} = -15V, I_D = -12A$ $V_{GS} = -10V$		88.0		nC
Gate-Source Charge	Qgs			14.0		nC
Gate-Drain Charge	Qgd			8.5		nC
<b>DRAIN-SOURCE DIODE CHARACTERISTICS</b>						
Drain-Source Diode Forward Current (Note 1)	$I_S$				-2.1	A
Diode Forward Voltage (Note 3)	$V_{SD}$	$V_{GS} = 0V, I_S = I_F$			-1.2	V

Note:

3. Pulse Test Pulse width  $\leq 300\mu s$ , Duty Cycle  $\leq 2\%$ .

4. Guaranteed by design, not subject to production testing.

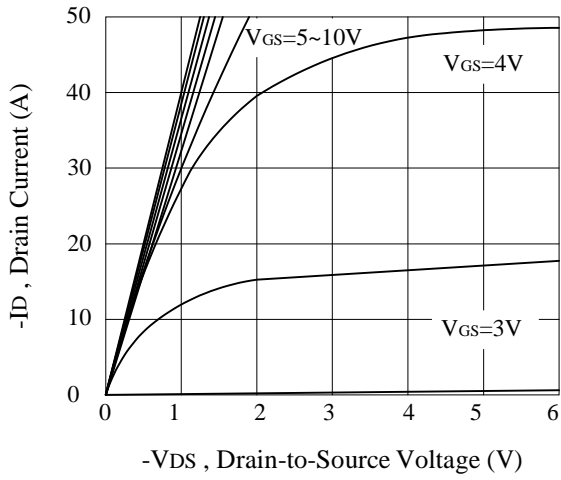


Figure 1. Output Characteristics

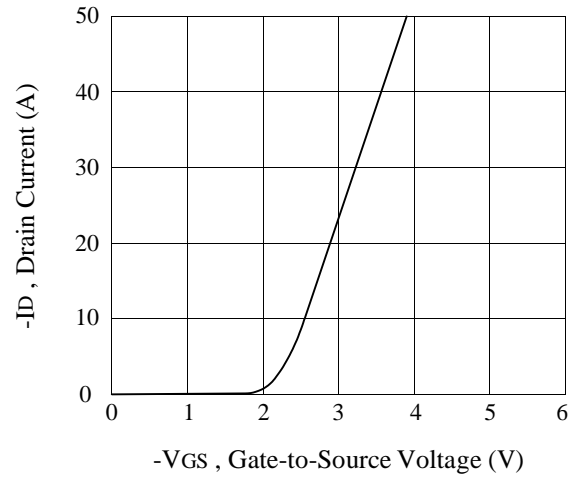


Figure 2. Transfer Characteristics

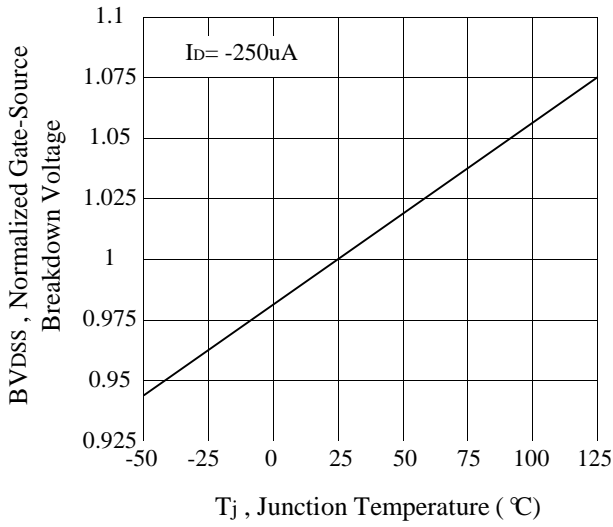


Figure 3. Breakdown Voltage Variation with Temperature

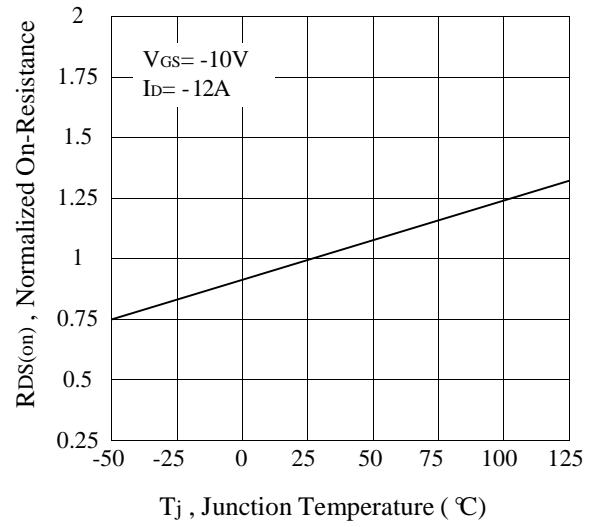


Figure 4. On-Resistance Variation with Temperature

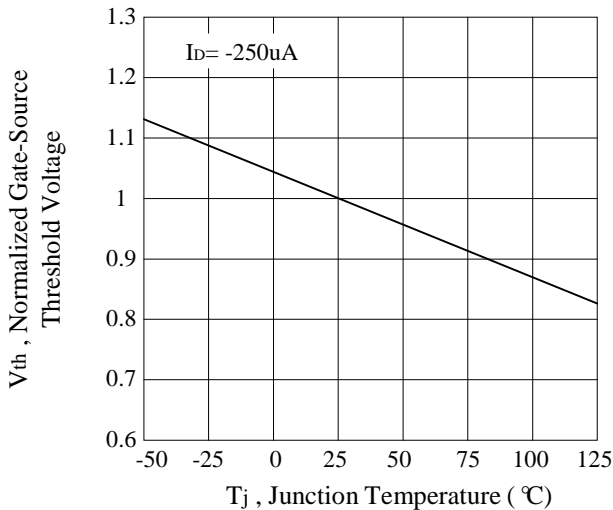


Figure 5. Gate Threshold Variation with Temperature

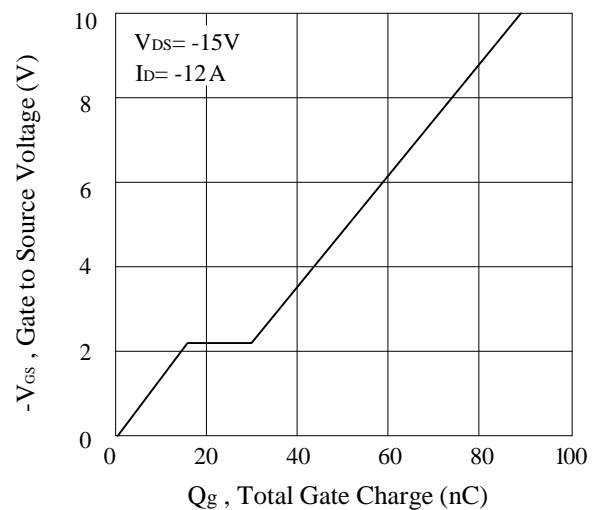
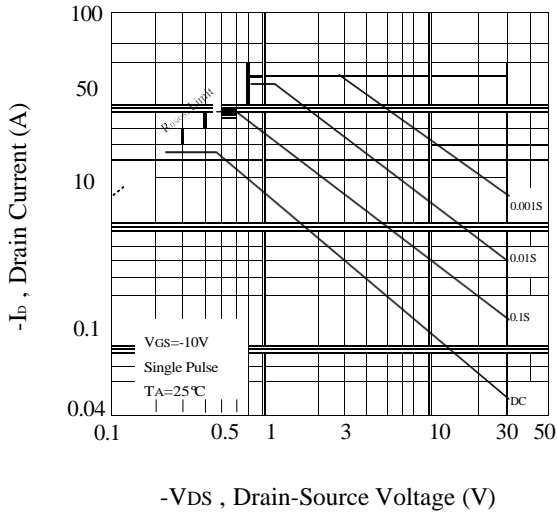
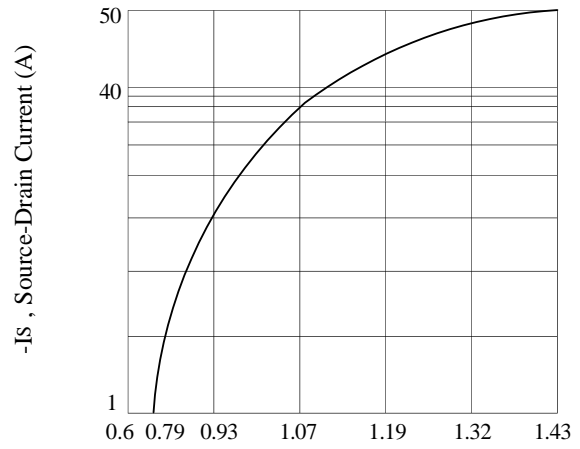


Figure 6. Gate Charge

# P-Channel High Density Trench MOSFET



-VDS, Drain-Source Voltage (V)  
 Figure 7. Maximum Safe Operating Area



-VSD, Body Diode Forward Voltage (V)  
 Figure 1. Body Diode Forward Voltage Variation with Source Current

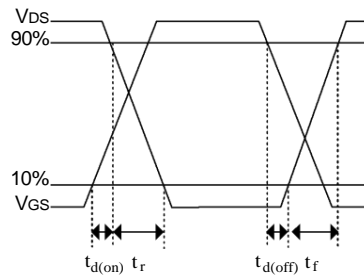
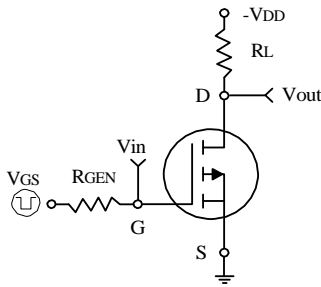


Figure 9. Switching Test Circuit and Switching Waveforms

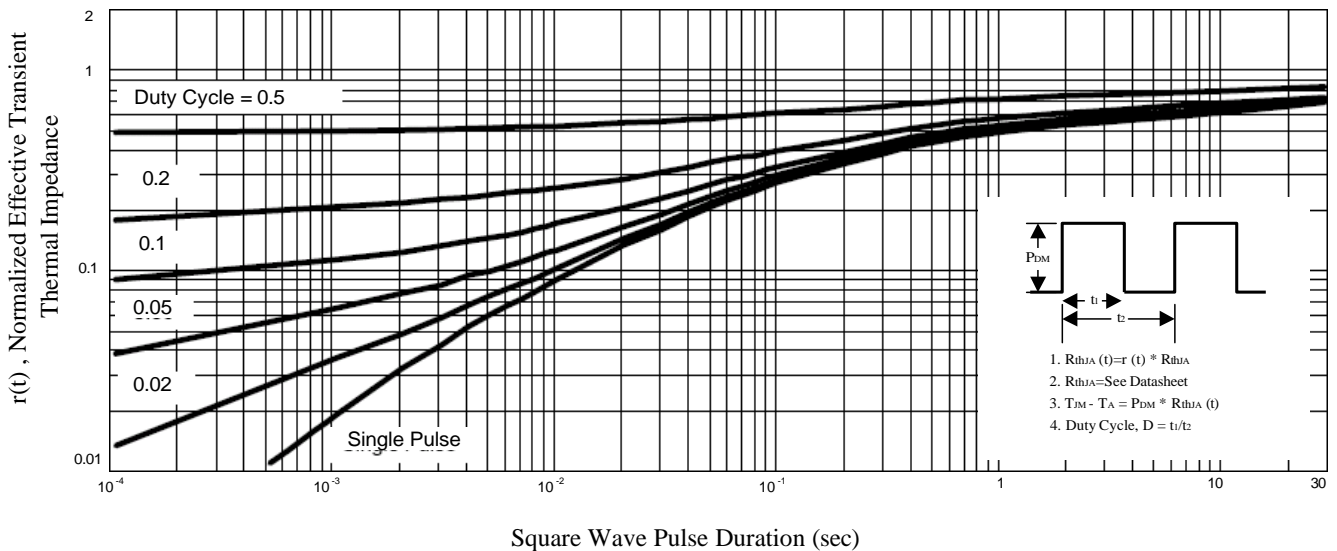


Figure 10. Normalized Thermal Transient Impedance Curve